

ZXMN2F34MA 20V N-channel enhancement mode MOSFET in DFN322

Summary

V _{(BR)DSS}	R _{DS(on)} (Ω)	I _D (A)
20	0.060 @ V _{GS} = 4.5V	8.5
	0.120 @ V _{GS} = 2.5V	

Description

This new generation Trench MOSFET from Zetex features low onresistance achievable with low (2.5V) gate drive. The 2mm x 2mm DFN package provides superior thermal performance versus alternative leaded devices

Features

- Low on-resistance
- Superior thermal performance (versus to SOT23)
- 2.5V gate drive capability
- DFN 2x2 package

Applications

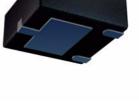
- Buck/Boost DC-DC Converters
- Motor Control
- LED Lighting

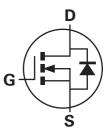
Ordering information

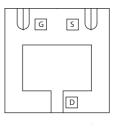
DEVICE	Reel size	Tape width	Quantity
	(inches)	(mm)	per reel
ZXMN2F34MATA	7	8	3,000

Device marking

1M4







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Absolute maximum ratings

Parameter	Symbol	Limit	Unit
Drain source voltage	V _{DSS}	20	V
Gate source voltage	V _{GS}	±12	V
$\begin{array}{c} \mbox{Continous Drain Current} @ V_{GS} = 4.5; \ T_A = 25^{\circ}C^{(b)} \\ @ V_{GS} = 4.5; \ T_A = 70^{\circ}C^{(b)} \\ @ V_{GS} = 4.5; \ T_A = 25^{\circ}C^{(a)} \\ @ V_{GS} = 4.5; \ T_A = 25^{\circ}C^{(d)} \end{array}$	ID	5.1 4.1 4.0 8.5	A A A A
Pulsed drain current ^(c)	I _{DM}	19	А
Continuous source current (body diode) ^(b)	ا _S	3.1	А
Pulsed source current (body diode) ^(c)	I _{SM}	19	А
Power dissipation at T _A =25°C ^(a) Linear derating factor	PD	1.35 10.8	W mW/°C
Power dissipation at T _A =25°C ^(b) Linear derating factor	P _D	2.2 17.8	W mW/°C
Power dissipation at T _A =25°C ^(d) Linear derating factor	P _D	6.6 52.9	W mW/°C
Operating and storage temperature range	T _j , T _{stg}	-55 to 150	°C

Thermal resistance

Parameter	Symbol	Limit	Unit
Junction to ambient ^(a)	$R_{\Theta JA}$	92.5	°C/W
Junction to ambient ^(b)	$R_{\Theta JA}$	56	°C/W
Junction to lead ^(d)	R _{ƏJL}	18.9	°C/W

NOTES:

(a) For a device surface mounted on 25mm x 25mm FR4 PCB with high coverage of single sided 1oz copper, in still air conditions.

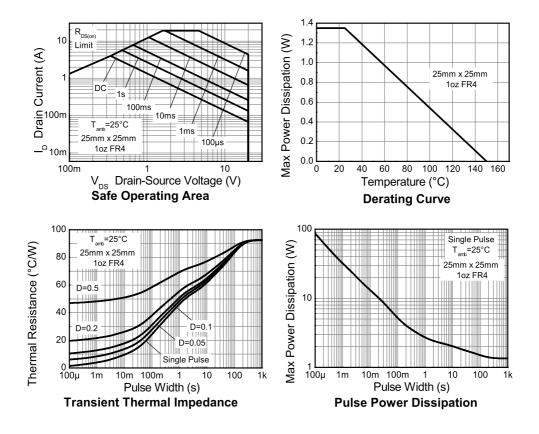
(b) For a device surface mounted on FR4 PCB measured at ts 5 sec.

(c) Repetitive rating - 25mm x 25mm FR4 PCB, D=0.02, pulse width 300μ s - pulse width limited by maximum junction temperature.

(d) Thermal resistance from junction to solder-point (at end of drain lead).

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Thermal characteristics



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Electrical characteristics (at $T_{amb} = 25^{\circ}C$ unless otherwise stated)

Parameter	Symbol	Min.	Тур.	Max.	Unit	Conditions	
Static				1			
Drain-Source breakdown voltage	V _{(BR)DSS}	20			V	I _D = 250μA, V _{GS} =0V	
Zero gate voltage drain current	I _{DSS}			1	μA	V _{DS} = 20V, V _{GS} =0V	
Gate-Body leakage	I _{GSS}			100	nA	$V_{GS}=\pm 12V, V_{DS}=0V$	
Gate-Source threshold voltage	V _{GS(th)}	0.5	0.8	1.5	V	I_{D} = 250µA, V_{DS} = V_{GS}	
Static Drain-Source on-state resistance ^(*)	R _{DS(on)}			0.060 0.120	Ω Ω	V _{GS} = 4.5V, I _D = 2.5A V _{GS} = 2.5V, I _D = 1.0A	
Forward transconductance ^{(*)(†)}	9 _{fs}		7.5		S	V _{DS} = 10V, I _D = 2.5A	
Dynamic ^(†)							
Input capacitance	C _{iss}		277		pF		
Output capacitance	C _{oss}		65		pF	V _{DS} = 10V, V _{GS} =0V f=1MHz	
Reverse transfer capacitance	C _{rss}		35		pF		
Switching ^{(‡)(†)}			•				
Turn-on-delay time	t _{d(on)}		2.65		ns		
Rise time	t _r		4.2		ns	V _{DD} = 10V, V _{GS} = 4.5V I _D = 1A	
Turn-off delay time	t _{d(off)}		9.9		ns	$R_{G} \approx 6.0\Omega$	
Fall time	t _f		5.1		ns		
Total gate charge	Qg		2.8		nC	V_{DS} = 10V, V_{GS} = 4.5V	
Gate-Source charge	Q _{gs}		0.61		nC	I _D = 2.5A	
Gate Drain charge	0 _{gd}		0.63		nC	1	
Source-drain diode			•			•	
Diode forward voltage ^(*)	V _{SD}		0.73	1.2	V	I _S = 1.25A, V _{GS} =0V	
Reverse recovery time ^(†)	t _{rr}		6.5		ns	T _j =25°C, I _F =1.65A	
Reverse recovery charge ^(†)	0 _{rr}		1.4		nC	di/dt=100A/µs	

NOTES:

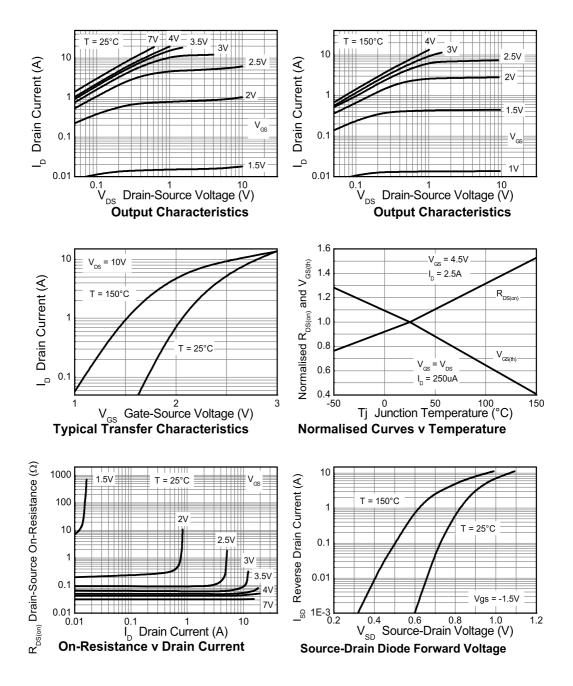
(*) Measured under pulsed conditions. Pulse width \leq 300 μs ; duty cycle \leq 2%.

(†) For design aid only, not subject to production testing.

(‡) Switching characteristics are independent of operating junction temperature.

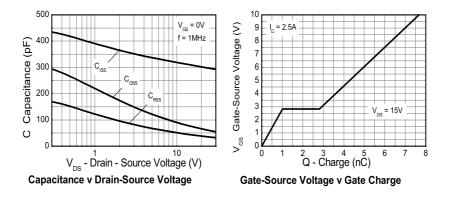
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Typical characteristics

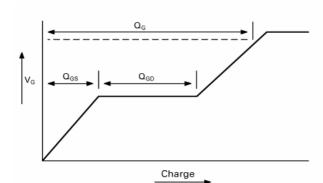


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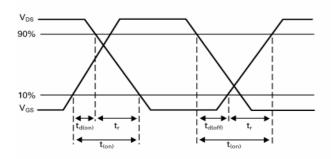
Typical characteristics



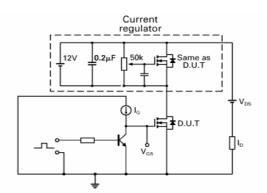
Test circuits



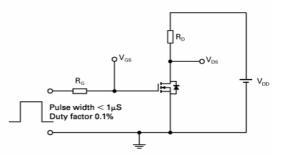
Basic gate charge waveform



Switching time waveforms



Gate charge test circuit



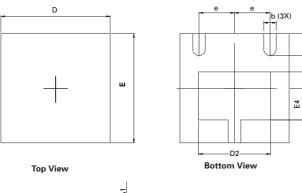
Switching time test circuit

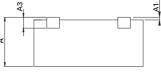
(3X)

E2

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Package outline - DFN322





Side View

DIM	Millin	neters	Inc	hes	DIM	Millimeters		Inches	
	Min.	Max.	Min.	Max.		Min.	Max.	Min.	Max.
А	0.80	1.00	0.0315	0.0393	D2	1.22	1.42	0.0480	0.0559
A1		0.05		0.002	е	0.65 BSC. 0.025		0.0255	9 BSC
A3	0.153	0.253	0.0060	0.0099	E	1.900	2.100	0.0748	0.0826
b	0.180	0.300	0.0071	0.0118	E2	0.780	0.990	0.0307	0.0389
D	1.900	2.100	0.0748	0.0826	E4	0.480	0.680	0.0189	0.0267
					L	0.300	0.500	0.0118	0.0196

Note: Controlling dimensions are in millimeters. Approximate dimensions are provided in inches

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Zetex sales offices

Europe	Americas	Asia Pacific	Corporate Headquarters
Zetex GmbH Kustermann-Park Balanstraße 59 D-81541 München Germany	Zetex Inc 700 Veterans Memorial Highway Hauppauge, NY 11788 USA	Zetex (Asia Ltd) 3701-04 Metroplaza Tower 1 Hing Fong Road, Kwai Fong Hong Kong	Zetex Semiconductors plc Zetex Technology Park, Chadderton Oldham, OL9 9LL United Kingdom
Telefon: (49) 89 45 49 49 0 Fax: (49) 89 45 49 49 49 europe.sales@zetex.com	Telephone: (1) 631 360 2222 Fax: (1) 631 360 8222 usa.sales@zetex.com	Telephone: (852) 26100 611 Fax: (852) 24250 494 asia.sales@zetex.com	Telephone: (44) 161 622 4444 Fax: (44) 161 622 4446 hq@zetex.com

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